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An Experimental Investigation of Residual Stress Development in Selective Laser Melting of Ti-6AI-4V

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- Motivation and background
- Materials and procedures
- Results
- Conclusions
- Future Work









- •Advantages of Selective Laser Melting (SLM) Additive Manufacturing (AM) Compared to Other Processes:
 - Produces high resolution
 - Complex internal passages
 - Dimensional control

SLM Disadvantages:

- Produces large thermal gradients that produce undesirable residual stress
- Residual stress (RS) causes thermal cracking and build distortion in AM which results in build failure

Objective: Develop methods to measure and control residual stress in SLM builds



Frazier et al. (2014)



Ti64 AM build distortion



Background: Residual Stresses in SLM

- Prior Literature Observations:
 - Melt pool cooling rate can be tailored to reduce residual stress
 - Process parameters (e.g. laser power, scan speed, hatch spacing, dwell time, and scan strategy) can affect the evolution of residual stress
 - Substrate preheating and support structure can reduce residual stress
- Previous work fails to establish:
 - The effect of substrate geometry, thickness, confinement, and overhang on residual stress
 - The effect of process parameters on residual stress
 - The effect of prior build-plate condition on AM residual stress
 - Effect of measurement method (e.g. XRD, Hole Drilling, Contour Method, and Layer removal method) on residual stress











Program Material & AM System



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Program Material

- Ti-6AI-4V substrate and Ti-6AI-4V AM powder
- Average diameter of Ti64 powder particles: 23.4 µm
- As-received substrate microstructure: 93% alpha and 7% beta by area fraction
 - Substrates cut from a 28" x 24" plate that had a thickness of 5/16"
 - Substrates dimensions were 76.2 mm x 76.2 mm x 7.93 mm and 25.4 mm x 25.4 mm x 7.93 mm

SLM System

- \bullet IPG 500 W Laser with a spotsize of 50 μm
- F-theta lens with 6 inch focal length
- AM system enables customized process
 design





As-Received powder

Microstructure of as-received Ti64 substrate



UTC SLM AM system





Initial Substrate Heat Treatments to Eliminate Residual Stresses



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Alpha/Beta Furnace HT

Alpha/Beta Vacuumed HT

Beta Vacuum HT









DoE for (25.4 x 25.4 x *h*)mm AM Builds



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Surface RS Measurements

- XRD Measurements
- Hole Drilling Measurements
- XRD vs. Hole Drilling Measurements

Subsurface RS Measurements

Layer Removal Method



Effect of Substrate Condition on XRD RS



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- Largest measured stresses were always parallel to the laser track direction
- Initial substrate stress <u>does</u> <u>affect</u> AM build surface residual stress
- Higher laser power and smaller stripe width decreased surface residual stress



1.6 mm AM build and laser glaze







Effect of AM Build Plan Area on XRD RS



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- Largest measured stresses were always parallel to laser track direction
- Back surface residual stress increased as AM build volume increased
- Substrate distortion increased as AM build volume increased









Effect of Substrate with no Overhang on XRD RS



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- Principal stresses were parallel and perpendicular to the laser track direction with respect to the *final* deposited layer
- AM builds fabricated on substrates with no overhang exhibited lower top surface and substrate backside residual stress compared to substrate with overhang



- Top Surface Residual Stress on 76.2 mm x 76.2 mm x 7.93 mm Substrate
- Top Surface Residual Stress on 25.4 mm x 25.4 mm x 7.93 mm Substrate

AM Builds on Stress Relieved Substrates



AM build with no substrate overhang DISTRIBUTION A: Approved for public release; distribution unlimited. (88ABW-2017-3698)



Effect of Scan Speed on XRD RS



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Top Surface Residual Stress



Top surface residual stress increased as scan speed increased





Hole Drilling RS Measurements



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0.50"



Hole Drilling Locations on AM Deposits





Hole Drilling RS Measurements



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Substrate Back Surface Residual Stress 500 Residual Stress (MPa) 400 300 XRD Measurements AND Measurements 200 HD Measurements -▲ •HD Measuremetns 100 0 Laser Glaze 1.587 mm 12.7 mm 25.4 mm **AM Build Height**



Hole Drilling Location on Substrate Back Surface





Hole Drilling RS Measurements



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Top Surface Residual Stress



Hole Drilling Locations on AM Deposits









Surface RS Measurements

- XRD Measurements
- Hole Drilling Measurements
- XRD vs. Hole Drilling Measurements

Subsurface RS Measurements

Layer Removal Method





Layer Removal Method

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Instantaneous Height (mm)

25.4 mm AM Build



Instantaneous Height (mm)

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Layer-removal-method sample



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- Higher laser power, lower scan speed, smaller stripe width, reduction in substrate overhang, reduction in plan area all decrease top-surface residual stress
- There are similarities and differences among the different measurement techniques









- Determine x-ray elastic constants for Ti64 substrates and additively manufactured Ti64
- Determine texture of AM builds (EBSD)
- Determine Knoop hardness yield loci to assess plastic anisotropy









